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## Regional Correspondents

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### *Japan*

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## Calendar of Meetings

### 1994

#### 8–10 March

**International Centre for Diffraction Data Spring Technical Meetings and Annual Meeting**, ICDD Headquarters, Newtown Square, Pennsylvania, USA. [Contact: Ms. Josephine Felizzi, International Centre for Diffraction Data, Newtown Square Corporate Campus, 12 Campus Boulevard, Newtown Square, PA 19073-3273, USA. Phone (215) 325-9814].

#### 4–8 April

**Materials Research Society**, San Francisco, California, USA [Contact: Materials Research Society, Meetings Department, 9800 McKnight Road, Suite 327, Pittsburgh, PA 15237, USA. Phone (412) 367-3003; FAX (412) 367-4373].

#### June 1994

**ICDD Clinic on X-Ray Powder Diffraction, 6–10 June 1994, Fundamentals; 13–17 June 1994, Advanced Techniques**, ICDD Headquarters, Newtown Square Pennsylvania, USA. The ICDD X-Ray Clinics are the continuation of the SUNY Clinics which, for some 25 years, were held at the State University of New York at Albany. The ICDD assumed responsibility for these clinics in 1990. The Clinic is presented in two separate week-long sessions, each of which stands alone as a complete course. [Contact: Mario Fornoff, ICDD X-Ray Clinic, ICDD Headquarters, Newtown Square Corporate Campus, 12 Campus Boulevard, Newtown Square, PA 19073-3273, USA. Phone (215) 325-9810].

#### 12–13 June

**International Conference on Powder Diffraction**, St. Petersburg, Russia. Topics to be covered at this conference will include New Developments in Traditional Powder Diffraction Methods and Databases; Novel Applications and Structural Science; High-Temperature and High-

Pressure Diffraction and Crystal Chemistry; New Achievements in Crystal Chemistry on the Basis of X-ray Powder Data; Neutron, Electron, and Synchrotron X-ray Diffraction for Crystal Chemistry; and New Developments in hardware. [Contact: Professor S. K. Filatov, Department of Crystallography, St. Petersburg University, 7/9 University Emb., St. Petersburg 199034, Russia. Phone (7 812) 2189 647; FAX (7 812) 2181 346].

#### July 1994

**ICDD Clinic on X-Ray Fluorescence Spectroscopy, 20–24 June 1994, Fundamentals; 27 June–1 July 1994, Advanced Techniques**, ICDD Headquarters, Newtown Square, Pennsylvania, USA. [Details and Contact: Same as ICDD Clinic on X-Ray Powder Diffraction (above)].

#### 1–5 August

**1994 Annual Denver Conference on Applications of X-Ray Analysis**, Steamboat Springs, Colorado, USA. [Contact: Lynne Bonno, Conference Secretary, Department of Engineering, University of Denver, Denver, CO 80208, USA. Phone (303) 871-3515].

#### 22–26 August

**XVI International Conference on Applied Crystallography**, Cieszyn, Poland. [Topics to be covered will include Real Structure of Materials (Metals, Ceramics, Polymers, etc.); Relationship between Structure and Properties; Crystallography of Phase Transformations; Methodological Development in Applied Crystallography (Phase Identification, Precision Measurement of Lattice Constants, Determination of Crystallite Size and Distortion, Texture, High-temperature X-ray Techniques, Small Angle Scattering, X-ray Topography, Diffraction Line Analysis, Electron and Neutron Diffraction, Software, and Databases). [Contact: Dr. Danuta Stroz, Conference Secretary, University of Silesia, Institute of Physics and Chemistry of Metals, Bankowa 12, 40-007 Katowice, Poland. Phone (048) 59-69-29, E-mail: dana@usctouxl.cta.us.edu.pl].

28 August–2 September

**Fifteenth European Crystallographic Meeting (ECM-15)**, Dresden, Germany. The scientific programme will include invited lectures, microsymbosia, and poster sessions. The first circular lists 19 main topics of the conference. [Contact: Professor P. Paufler, Institut für Kristallographie, Fachbereich Physik, Technische Universität Dresden, Mommsenstr. 13, D-0-8027, Dresden, Germany. Phone [+ [37] 51] 463 33 78, E-mail: paufler@physik.tu-dresden.dbp.de].

12–13 October

**International Centre for Diffraction Data Fall Technical Meetings**, ICDD Headquarters, Newtown Square, Pennsylvania, USA. [Contact: Ms. Josephine Felizzi, International Centre for Diffraction Data, Newtown Square Corporate Campus, 12 Campus Boulevard, Newtown Square, PA 19073-3273, USA. Phone (215) 325-9814].

December 1994

**Materials Research Society Fall Meeting**, Boston, Massachusetts, USA. [Contact: Materials Research Society, Meetings Department, 9800 McKnight Road, Suite 327, Pittsburgh, PA 15237, USA. Phone (412) 367-3003; FAX (412) 367-4373].

1995

6–11 August

**Sixteenth European Crystallographic Meeting (ECM-16)**, Lund, Sweden. The meeting is intended as a forum for interdisciplinary contacts between all diverse subfields of crystallography. The programme committee is anxious to attract all types of crystallographic contributions. [Contact: Ake Oskarsson (Chairman of the Organizing Committee), Department of Inorganic Chemistry 1, Chemical Center, Lund University, P.O. Box 124, S-221 00 Lund, Sweden. Phone: Int+46 46 108102. E-mail: Ake.Oskarsson@INORGK1.LU.SE].

1996

8–17 August

**Seventeenth IUCr General Assembly and International Congress of Crystallography**. Seattle, Washington, USA. [Contact: Professor R. F. Bryan, Department of Chemistry, University of Virginia, Charlottesville, VA 22903, USA].

## Book Reviews

*A word from the editor: It was quite a surprise to receive two book reports on The Rietveld Method, one by the Editor-in-Chief, Deane K. Smith, and the other by International Correspondent Jaroslav Fiala. After finding that the two reviews gave different information, I decided to have both of them included in this issue.*

Helein D. Hitchcock

### THE RIETVELD METHOD

R. A. Young, Editor

*IUCr Monographs in Crystallography, 5, International Union of Crystallography, Oxford University Press, New York, NY, pp. 298.*

This timely publication contains a wealth of information on one of the most powerful techniques in diffraction crystallography. It results from an International Workshop on the Rietveld Method held in Petten, The Netherlands, 13–15 June 1989, which was hosted by the Netherlands Energy Research Foundation ECN and sponsored by the International Union of Crystallography Commission on Powder Diffraction.

This book is not a Proceedings, rather it is designed to be tutorial for diffractionists who want to apply the Rietveld method to real problems. The authors were all speakers at the Workshop, but they have expended considerable extra effort to prepare their chapters into a coherent text rather than as independent papers that typify a Proceedings. The extended time of 4 years between the Workshop and the publication is indicative of this effort. The product is an excellent reference publication and also a first-rate text for specialized training or educating readers

in this important technique. It is a fine example of the role of the International Union of Crystallography in promoting good science.

The publication is composed of 15 chapters that cover the mathematics and physics of the Rietveld procedure and its relation to structure analysis and materials characterization by other methods. All the authors—some chapters have more than one author—are among the leaders in the development and implementation of the theory and practice of Rietveld analyses. Other than Chapter 1, which is a general introduction, and Chapter 2, which is a historical account by Hugo Rietveld, all the chapters are directed to a well-defined topic on the mathematical and physical theory and use of the technique. The level of the presentations requires some experience with the technique and the programs involved, but even beginners can get sufficient information in a first reading to get off to a good start. In fact, it is impossible for anyone to assimilate all this book has to offer in any one reading. The mathematics are described in an instructive manner with descriptive documentation but without derivations. The physics of each aspect is presented along with the mathematics. There is considerable discussion on the proper profile to use in the fitting procedure and the interpretation of the different profiles encoun-